

W1.1 @ PICS 2001

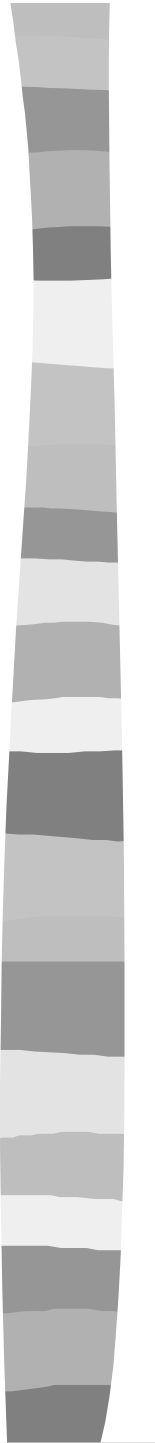
Microuniformity Sub-group



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Montreal, Canada



W1.1 Sub-group on MicroUniformity

- Members: George Chiu--Purdue University, Marguerite Doyle--Lexmark, Frans Gaykema--Oce, Paul Kane--Kodak, Terry Nelson--HP, Rene Rasmussen--Xerox, Eric Zeise--NexPress, Robert Zeman--Kodak, chair



Accomplishments

- Identified 5 sub-attributes of uniformity
- Constructed visual definitions thereof
- Initiated JPEGs of attributes on W1.1
- Agreed to standardize viewing distance
- Resolved Micro/Macro uniformity approaches



Uniformity Sub-attributes

- Streaks: 1-D random line-like structures
- Bands: 1-D uniformly periodic line-like structures
- Voids: Pinhole type defects
- Textures: Moire & patterns with correlated phase
- Noise: 2-D random lightness fluctuation



Current Status

- Just finishing macro/micro joint teleconferences
- Combined these meetings to address ‘full spectrum’ of uniformity
- About to begin discussion of target generation and measurement procedures